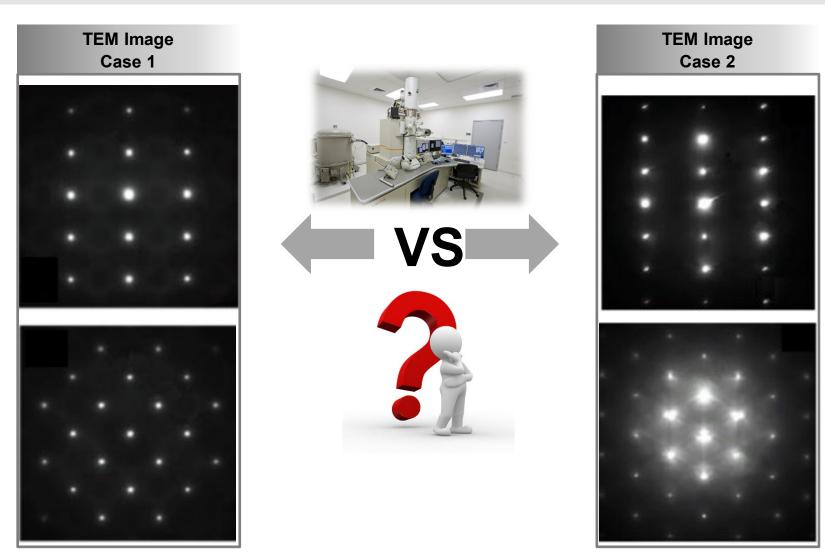


Al based material crystal structure analysis solution

LightVision Inc. 2023-06-21

TEM Image Analysis

Analyzing 2D patterns in TEM(Transmission Electron Microscope) images to infer the 3D crystal structure of the material





AI based TEM SAED Pattern Analysis

[Existing TEM SAED pattern analysis method]

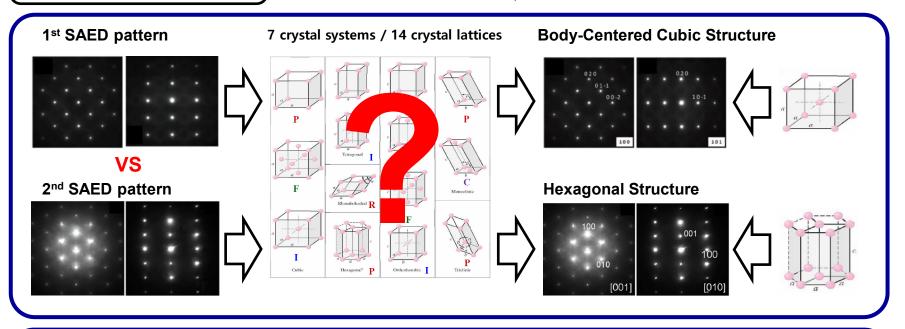
- · Domain knowledge required
- · Take very long time to analyze the pattern



Al based **TEM SAED** analysis S/W



Crystal structure classification





BiRh (SG: 194)



C (SG: 227)



Pt (SG: 225)



He (SG: 229)

Real SEM/TEM Image Generation Technology

Golden Template based Defect Analysis

PROBLEM



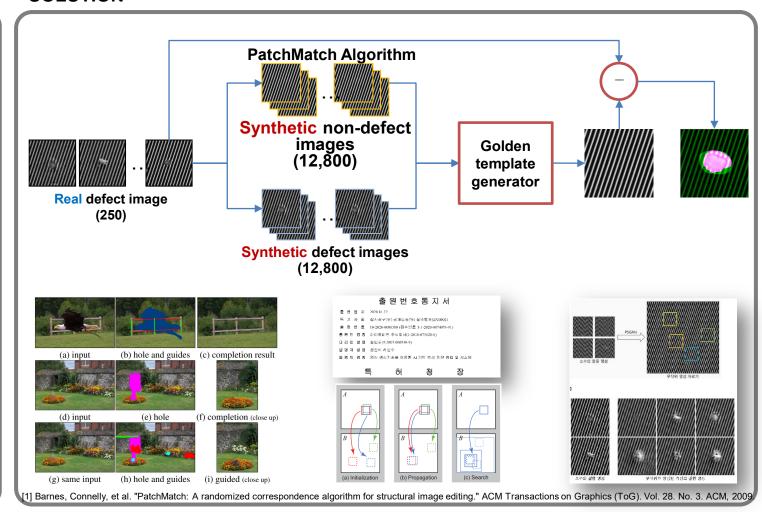
Lack of data



Data imbalance

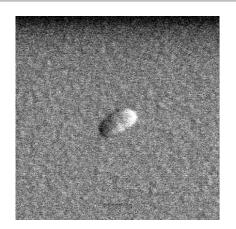


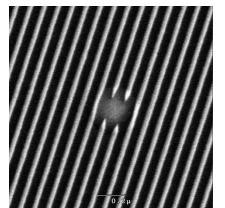
SOLUTION



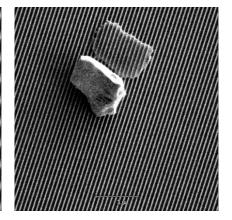
Defect Detection in SEM Image through AI Engine

Semiconductor defect detection in Scanning Electron Microscope (SEM) images

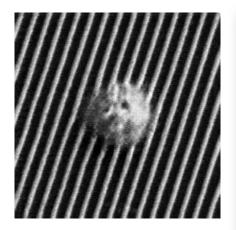




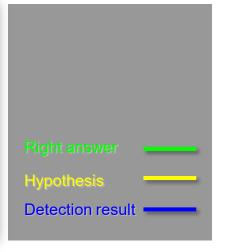




Detecting various type of defects through an Al engine

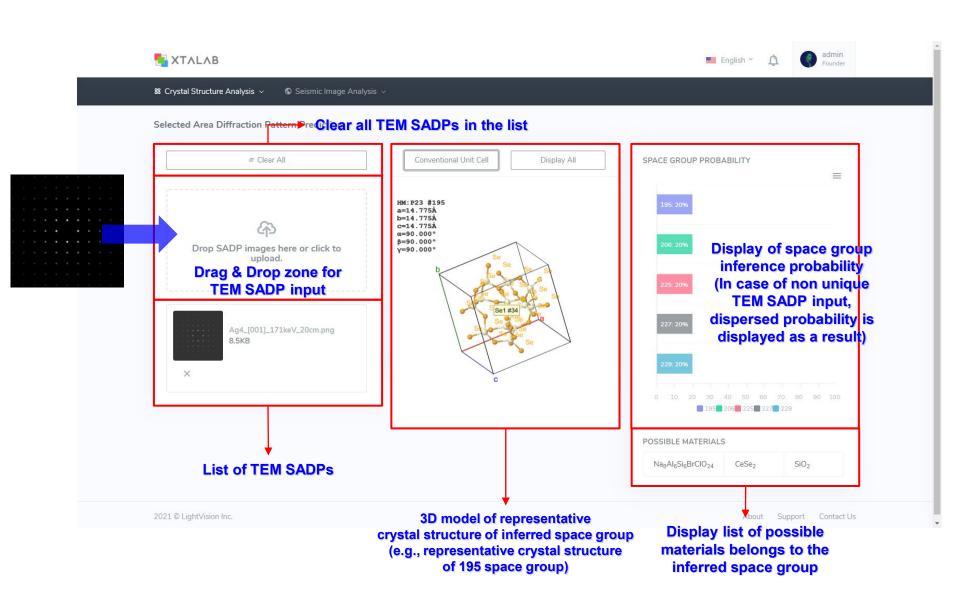






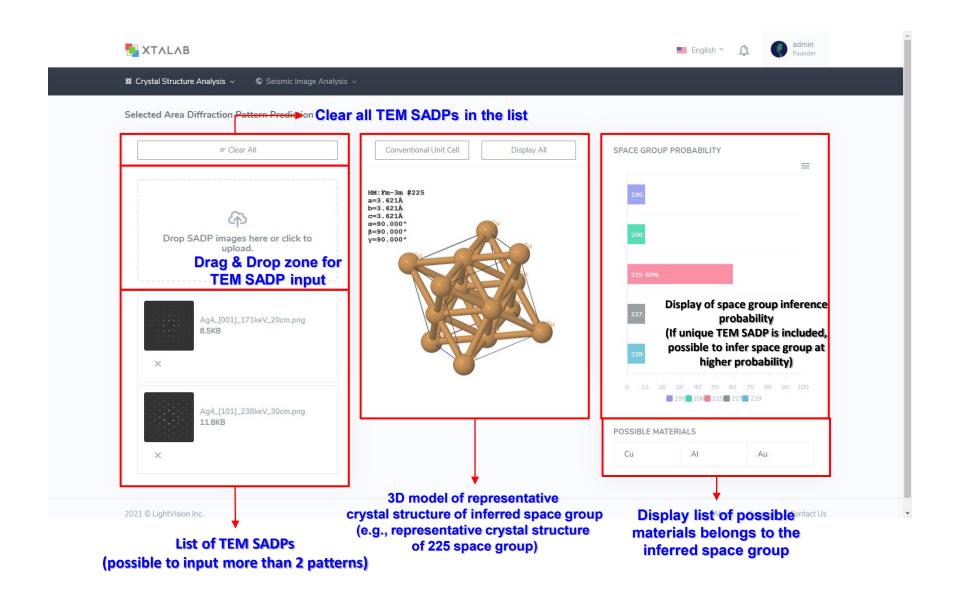


Automatic analysis of TEM SADP



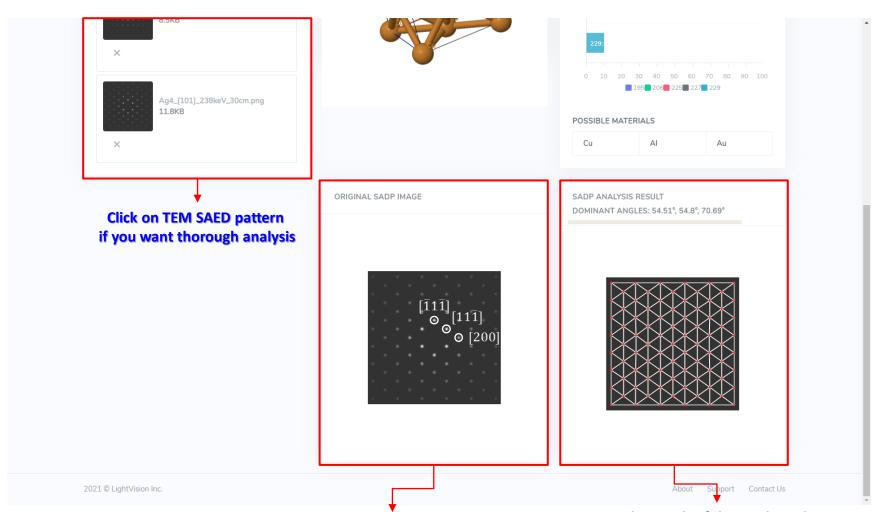


Automatic analysis of TEM SADP





Thorough analysis of TEM SADP



Display an original of the analyzed TEM SAED pattern (automatic indexing)

Display result of thorough analysis (distances and angles between diffraction spots)

